

Contents

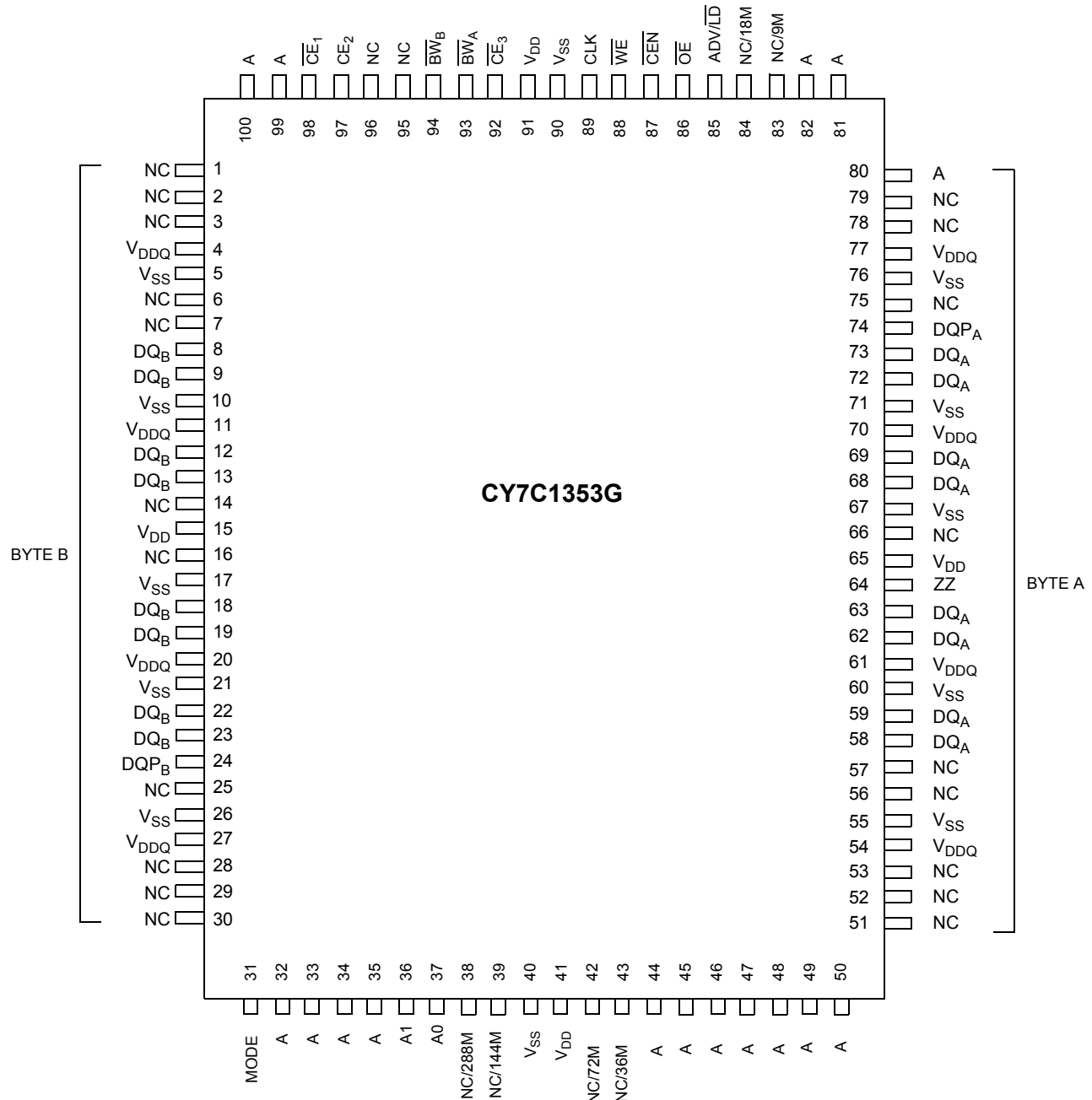
Selection Guide	3	Switching Characteristics	10
Pin Configuration	3	Switching Waveforms	11
Pin Definitions	4	Ordering Information	13
Functional Overview	5	Ordering Code Definitions	13
Single Read Accesses	5	Package Diagram	14
Burst Read Accesses	5	Acronyms	15
Single Write Accesses	5	Document Conventions	15
Burst Write Accesses	6	Units of Measure	15
Sleep Mode	6	Errata	16
Linear Burst Address Table	6	Part Numbers Affected	16
Interleaved Burst Address Table	6	Product Status	16
ZZ Mode Electrical Characteristics	6	Ram9 NoBL ZZ Pin Issues Errata Summary	16
Truth Table	7	Document History Page	17
Partial Truth Table for Read/Write	7	Sales, Solutions, and Legal Information	19
Maximum Ratings	8	Worldwide Sales and Design Support	19
Operating Range	8	Products	19
Electrical Characteristics	8	PSoC@Solutions	19
Capacitance	9	Cypress Developer Community	19
Thermal Resistance	9	Technical Support	19
AC Test Loads and Waveforms	9		

Selection Guide

Description	100 MHz	Unit
Maximum access time	8.0	ns
Maximum operating current	205	mA
Maximum CMOS standby current	40	mA

Pin Configuration

Figure 1. 100-pin TQFP (14 × 20 × 1.4 mm) pinout ^[1]



Note

- Errata:** The ZZ pin (Pin 64) needs to be externally connected to ground. For more information, see "Errata" on page 16.

Pin Definitions

Name	I/O	Description
A ₀ , A ₁ , A	Input-synchronous	Address inputs used to select one of the 256K address locations. Sampled at the rising edge of the CLK. A _[1:0] are fed to the two-bit burst counter.
BW _[A:B]	Input-synchronous	Byte write inputs, active LOW. Qualified with \overline{WE} to conduct writes to the SRAM. Sampled on the rising edge of CLK.
\overline{WE}	Input-synchronous	Write enable input, active LOW. Sampled on the rising edge of CLK if \overline{CEN} is active LOW. This signal must be asserted LOW to initiate a write sequence.
ADV/LD	Input-synchronous	Advance/load input. Used to advance the on-chip address counter or load a new address. When HIGH (and CEN is asserted LOW) the internal burst counter is advanced. When LOW, a new address can be loaded into the device for an access. After being deselected, ADV/LD must be driven LOW to load a new address.
CLK	Input-clock	Clock input. Used to capture all synchronous inputs to the device. CLK is qualified with \overline{CEN} . CLK is only recognized if \overline{CEN} is active LOW.
\overline{CE}_1	Input-synchronous	Chip enable 1 input, active LOW. Sampled on the rising edge of CLK. Used in conjunction with \overline{CE}_2 , and \overline{CE}_3 to select/deselect the device.
\overline{CE}_2	Input-synchronous	Chip enable 2 input, active HIGH. Sampled on the rising edge of CLK. Used in conjunction with \overline{CE}_1 and \overline{CE}_3 to select/deselect the device.
\overline{CE}_3	Input-synchronous	Chip enable 3 input, active LOW. Sampled on the rising edge of CLK. Used in conjunction with \overline{CE}_1 and \overline{CE}_2 to select/deselect the device.
\overline{OE}	Input-asynchronous	Output enable, asynchronous input, active LOW. Combined with the synchronous logic block inside the device to control the direction of the I/O pins. When LOW, the I/O pins are allowed to behave as outputs. When deasserted HIGH, I/O pins are tri-stated, and act as input data pins. \overline{OE} is masked during the data portion of a write sequence, during the first clock when emerging from a deselected state, when the device has been deselected.
\overline{CEN}	Input-synchronous	Clock enable input, active LOW. When asserted LOW the clock signal is recognized by the SRAM. When deasserted HIGH the clock signal is masked. While deasserting \overline{CEN} does not deselect the device, \overline{CEN} can be used to extend the previous cycle when required.
ZZ ^[2]	Input-asynchronous	ZZ “sleep” Input. This active HIGH input places the device in a non-time critical “sleep” condition with data integrity preserved. During normal operation, this pin has to be low or left floating. ZZ pin has an internal pull-down.
DQ _s	I/O-synchronous	Bidirectional data I/O lines. As inputs, they feed into an on-chip data register that is triggered by the rising edge of CLK. As outputs, they deliver the data contained in the memory location specified by address during the clock rise of the read cycle. The direction of the pins is controlled by \overline{OE} and the internal control logic. When \overline{OE} is asserted LOW, the pins can behave as outputs. When HIGH, DQ _s and DQP _[A:B] are placed in a tri-state condition. The outputs are automatically tri-stated during the data portion of a write sequence, during the first clock when emerging from a deselected state, and when the device is deselected, regardless of the state of \overline{OE} .

Note

2. **Errata:** The ZZ pin (Pin 64) needs to be externally connected to ground. For more information, see “Errata” on page 16.

Pin Definitions (continued)

Name	I/O	Description
DQP _[A:B]	I/O-synchronous	Bidirectional data parity I/O lines. Functionally, these signals are identical to DQ _s . During write sequences, DQP _[A:B] is controlled by BW _x correspondingly.
MODE	Input strap pin	MODE input. Selects the burst order of the device. When tied to GND selects linear burst sequence. When tied to V _{DD} or left floating selects interleaved burst sequence.
V _{DD}	Power supply	Power supply inputs to the core of the device.
V _{DDQ}	I/O power supply	Power supply for the I/O circuitry.
V _{SS}	Ground	Ground for the device.
NC, NC/9M, NC/18M, NC/36M, NC/72M, NC/144M, NC/288M	–	No Connects. Not internally connected to the die. NC/9M, NC/18M, NC/72M, NC/144M, NC/288M, are address expansion pins are not internally connected to the die.

Functional Overview

The CY7C1353G is a synchronous flow-through burst SRAM designed specifically to eliminate wait states during write-read transitions. All synchronous inputs pass through input registers controlled by the rising edge of the clock. The clock signal is qualified with the clock enable input signal (CEN). If CEN is HIGH, the clock signal is not recognized and all internal states are maintained. All synchronous operations are qualified with CEN. Maximum access delay from the clock rise (t_{CDV}) is 8.0 ns (100-MHz device).

Accesses can be initiated by asserting all three chip enables (\overline{CE}_1 , \overline{CE}_2 , \overline{CE}_3) active at the rising edge of the clock. If clock enable (CEN) is active LOW and ADV/LD is asserted LOW, the address presented to the device is latched. The access can either be a read or write operation, depending on the status of the write enable (\overline{WE}). BW_[A:B] can be used to conduct byte write operations.

Write operations are qualified by the write enable (\overline{WE}). All writes are simplified with on-chip synchronous self timed write circuitry.

Three synchronous chip enables (\overline{CE}_1 , \overline{CE}_2 , \overline{CE}_3) and an asynchronous output enable (\overline{OE}) simplify depth expansion. All operations (reads, writes, and deselections) are pipe lined. ADV/LD must be driven LOW after the device has been deselected to load a new address for the next operation.

Single Read Accesses

A read access is initiated when the following conditions are satisfied at clock rise: (1) CEN is asserted LOW, (2) \overline{CE}_1 , \overline{CE}_2 , and \overline{CE}_3 are all asserted active, (3) the write enable input signal \overline{WE} is deasserted HIGH, and 4) ADV/LD is asserted LOW. The address presented to the address inputs is latched into the address register and presented to the memory array and control logic. The control logic determines that a read access is in progress and allows the requested data to propagate to the output buffers. The data is available within 8.0 ns (100-MHz device) provided \overline{OE} is active LOW. After the first clock of the read access, the output buffers are controlled by \overline{OE} and the internal control logic. \overline{OE} must be driven LOW in order for the

device to drive out the requested data. On the subsequent clock, another operation (read/write/deselect) can be initiated. When the SRAM is deselected at clock rise by one of the chip enable signals, its output is tri-stated immediately.

Burst Read Accesses

The CY7C1353G has an on-chip burst counter that allows the user the ability to supply a single address and conduct up to four reads without reasserting the address inputs. ADV/LD must be driven LOW to load a new address into the SRAM, as described in the [Single Read Accesses](#) section. The sequence of the burst counter is determined by the MODE input signal. A LOW input on MODE selects a linear burst mode, a HIGH selects an interleaved burst sequence. Both burst counters use A0 and A1 in the burst sequence, and wraps around when incremented sufficiently. A HIGH input on ADV/LD increments the internal burst counter regardless of the state of chip enable inputs or \overline{WE} . \overline{WE} is latched at the beginning of a burst cycle. Therefore, the type of access (read or write) is maintained throughout the burst sequence.

Single Write Accesses

Write access are initiated when these conditions are satisfied at clock rise:

- CEN is asserted LOW
- \overline{CE}_1 , \overline{CE}_2 , and \overline{CE}_3 are all asserted active
- The write signal \overline{WE} is asserted LOW.

The address presented to the address bus is loaded into the address register. The write signals are latched into the control logic block. The data lines are automatically tri-stated regardless of the state of the \overline{OE} input signal. This allows the external logic to present the data on DQs and DQP_[A:B].

On the next clock rise the data presented to DQs and DQP_[A:B] (or a subset for byte write operations, see truth table for details) inputs is latched into the device and the write is complete. Additional accesses (read/write/deselect) can be initiated on this cycle.

The data written during the write operation is controlled by $BW_{[A:B]}$ signals. The CY7C1353G provides byte write capability that is described in the truth table. Asserting the write enable input (\overline{WE}) with the selected byte write select input selectively writes to only the desired bytes. Bytes not selected during a byte write operation remains unaltered. A synchronous self timed write mechanism has been provided to simplify the write operations. Byte write capability has been included to greatly simplify read/modify/write sequences, which can be reduced to simple byte write operations.

Because the CY7C1353G is a common I/O device, data must not be driven into the device while the outputs are active. The output enable (\overline{OE}) can be deasserted HIGH before presenting data to the DQs and $DQP_{[A:B]}$ inputs. Doing so tri-states the output drivers. As a safety precaution, DQs and $DQP_{[A:B]}$ are automatically tri-stated during the data portion of a write cycle, regardless of the state of \overline{OE} .

Burst Write Accesses

The CY7C1353G has an on-chip burst counter that allows the user the ability to supply a single address and conduct up to four write operations without reasserting the address inputs. ADV/LD must be driven LOW to load the initial address, as described in the [Single Write Accesses](#) section. When ADV/LD is driven HIGH on the subsequent clock rise, the chip enables (\overline{CE}_1 , \overline{CE}_2 , and \overline{CE}_3) and \overline{WE} inputs are ignored and the burst counter is incremented. The correct $BW_{[A:B]}$ inputs must be driven in each cycle of the burst write, to write the correct bytes of data.

Sleep Mode

The ZZ input pin is an asynchronous input. Asserting ZZ places the SRAM in a power conservation “sleep” mode. Two clock cycles are required to enter into or exit from this “sleep” mode.

While in this mode, data integrity is guaranteed. Accesses pending when entering the “sleep” mode are not considered valid nor is the completion of the operation guaranteed. The device must be deselected prior to entering the “sleep” mode. \overline{CE}_1 , \overline{CE}_2 , and \overline{CE}_3 , must remain inactive for the duration of t_{ZZREC} after the ZZ input returns LOW.

Linear Burst Address Table

(MODE = GND)

First Address A1:A0	Second Address A1:A0	Third Address A1:A0	Fourth Address A1:A0
00	01	10	11
01	10	11	00
10	11	00	01
11	00	01	10

Interleaved Burst Address Table

(MODE = Floating or V_{DD})

First Address A1:A0	Second Address A1:A0	Third Address A1:A0	Fourth Address A1:A0
00	01	10	11
01	00	11	10
10	11	00	01
11	10	01	00

ZZ Mode Electrical Characteristics

Parameter	Description	Test Conditions	Min	Max	Unit
I_{DDZZ}	Sleep mode standby current	$ZZ \geq V_{DD} - 0.2 V$	—	40	mA
t_{ZZS}	Device operation to ZZ	$ZZ \geq V_{DD} - 0.2 V$	—	$2t_{CYC}$	ns
t_{ZZREC}	ZZ recovery time	$ZZ \leq 0.2 V$	$2t_{CYC}$	—	ns
t_{ZZI}	ZZ active to sleep current	This parameter is sampled	—	$2t_{CYC}$	ns
t_{RZZI}	ZZ inactive to exit sleep current	This parameter is sampled	0	—	ns

Truth Table

The truth table for CY7C1353G follows. [3, 4, 5, 6, 7, 8, 9]

Operation	Address Used	\overline{CE}_1	CE_2	\overline{CE}_3	ZZ	ADV/LD	\overline{WE}	\overline{BW}_x	\overline{OE}	\overline{CEN}	CLK	DQ
Deselect cycle	None	H	X	X	L	L	X	X	X	L	L->H	Tri-state
Deselect cycle	None	X	X	H	L	L	X	X	X	L	L->H	Tri-state
Deselect cycle	None	X	L	X	L	L	X	X	X	L	L->H	Tri-state
Continue deselect cycle	None	X	X	X	L	H	X	X	X	L	L->H	Tri-state
READ cycle (begin burst)	External	L	H	L	L	L	H	X	L	L	L->H	Data out (Q)
READ cycle (continue burst)	Next	X	X	X	L	H	X	X	L	L	L->H	Data out (Q)
NOP/DUMMY READ (begin burst)	External	L	H	L	L	L	H	X	H	L	L->H	Tri-state
DUMMY READ (continue burst)	Next	X	X	X	L	H	X	X	H	L	L->H	Tri-state
WRITE cycle (begin burst)	External	L	H	L	L	L	L	L	X	L	L->H	Data in (D)
WRITE cycle (continue burst)	Next	X	X	X	L	H	X	L	X	L	L->H	Data in (D)
NOP/WRITE ABORT (begin burst)	None	L	H	L	L	L	L	H	X	L	L->H	Tri-state
WRITE ABORT (continue burst)	Next	X	X	X	L	H	X	H	X	L	L->H	Tri-state
IGNORE CLOCK EDGE (stall)	Current	X	X	X	L	X	X	X	X	H	L->H	–
SLEEP MODE	None	X	X	X	H	X	X	X	X	X	X	Tri-state

Partial Truth Table for Read/Write

The partial truth table for Read/Write for CY7C1353G follows. [3, 4, 10]

Function	\overline{WE}	\overline{BW}_A	\overline{BW}_B
Read	H	X	X
Write – no bytes written	L	H	H
Write byte A – (DQ _A and DQP _A)	L	L	H
Write byte B – (DQ _B and DQP _B)	L	H	L
Write all bytes	L	L	L

Notes

- X = "Don't Care," H = Logic HIGH, L = Logic LOW. \overline{BW}_x = L signifies at least one byte write select is active, \overline{BW}_x = valid signifies that the desired byte write selects are asserted, see truth table for details.
- Write is defined by \overline{BW}_x and \overline{WE} . See truth table for read/write.
- When a write cycle is detected, all IOs are tri-stated, even during byte writes.
- The DQs and DQP_[A:B] pins are controlled by the current cycle and the \overline{OE} signal. \overline{OE} is asynchronous and is not sampled with the clock.
- \overline{CEN} = H, inserts wait states.
- Device powers up deselected and the IOs in a tri-state condition, regardless of \overline{OE} .
- \overline{OE} is asynchronous and is not sampled with the clock rise. It is masked internally during write cycles. During a read cycle DQs and DQP_[A:B] = tri-state when \overline{OE} is inactive or when the device is deselected, and DQs and DQP_[A:B] = data when \overline{OE} is active.
- Table only lists a partial listing of the byte write combinations. Any combination of BW[A:D] is valid. Appropriate write is based on which byte write is active.

Maximum Ratings

Exceeding maximum ratings may impair the useful life of the device. These user guidelines are not tested.

Storage temperature -65 °C to +150 °C

Ambient temperature with power applied -55 °C to +125 °C

Supply voltage on V_{DD} relative to GND -0.5 V to +4.6 V

Supply voltage on V_{DDQ} relative to GND -0.5 V to V_{DD}

DC voltage applied to outputs in tri-state -0.5 V to $V_{DDQ} + 0.5 V$

DC input voltage -0.5 V to $V_{DD} + 0.5 V$

Current into outputs (LOW) 20 mA

Static discharge voltage (MIL-STD-883, method 3015) > 2001 V

Latch-up current > 200 mA

Operating Range

Range	Ambient Temperature (T_A)	V_{DD}	V_{DDQ}
Commercial	0 °C to +70 °C	3.3 V – 5% / + 10%	2.5 V – 5% to V_{DD}

Electrical Characteristics

Over the Operating Range

Parameter ^[11, 12]	Description	Test Conditions	Min	Max	Unit
V_{DD}	Power supply voltage		3.135	3.6	V
V_{DDQ}	I/O supply voltage		2.375	V_{DD}	V
V_{OH}	Output HIGH voltage	for 3.3 V I/O, $I_{OH} = -4.0$ mA	2.4	–	V
		for 2.5 V I/O, $I_{OH} = -1.0$ mA	2.0	–	V
V_{OL}	Output LOW voltage	for 3.3 V I/O, $I_{OH} = 8.0$ mA	–	0.4	V
		for 2.5 V I/O, $I_{OH} = 1.0$ mA	–	0.4	V
V_{IH}	Input HIGH voltage	for 3.3 V I/O	2.0	$V_{DD} + 0.3$	V
	Input HIGH voltage	for 2.5 V I/O	1.7	$V_{DD} + 0.3$	V
V_{IL}	Input LOW voltage ^[11]	for 3.3 V I/O	–0.3	0.8	V
	Input LOW voltage ^[11]	for 2.5 V I/O	–0.3	0.7	V
I_X	Input leakage current except ZZ and MODE	$GND \leq V_I \leq V_{DDQ}$	–5	5	μA
	Input current of MODE	Input = V_{SS}	–30	–	μA
		Input = V_{DD}	–	5	μA
	Input current of ZZ	Input = V_{SS}	–5	–	μA
		Input = V_{DD}	–	30	μA
I_{OZ}	Output leakage current	$GND \leq V_I \leq V_{DDQ}$, output disabled	–5	5	μA
I_{DD}	V_{DD} operating supply current	$V_{DD} = \text{Max.}$, $I_{OUT} = 0$ mA, $f = f_{MAX} = 1/t_{CYC}$	–	205	mA
I_{SB1}	Automatic CE power-down current – TTL inputs	$V_{DD} = \text{Max.}$, device deselected, $V_{IN} \geq V_{IH}$ or $V_{IN} \leq V_{IL}$, $f = f_{MAX}$, inputs switching	–	80	mA
I_{SB2}	Automatic CE power-down current – CMOS inputs	$V_{DD} = \text{Max.}$, device deselected, $V_{IN} \geq V_{DD} - 0.3$ V or $V_{IN} \leq 0.3$ V, $f = 0$, inputs static	–	40	mA
I_{SB3}	Automatic CE power-down current – CMOS inputs	$V_{DD} = \text{Max.}$, device deselected, $V_{IN} \geq V_{DDQ} - 0.3$ V or $V_{IN} \leq 0.3$ V, $f = f_{MAX}$, inputs switching	–	65	mA
I_{SB4}	Automatic CE power-down current – TTL inputs	$V_{DD} = \text{Max.}$, device deselected, $V_{IN} \geq V_{DD} - 0.3$ V or $V_{IN} \leq 0.3$ V, $f = 0$, inputs static	–	45	mA

Notes

11. Overshoot: $V_{IH(AC)} < V_{DD} + 1.5$ V (Pulse width less than $t_{CYC}/2$), undershoot: $V_{IL(AC)} > -2$ V (Pulse width less than $t_{CYC}/2$).

12. $T_{Power-up}$: Assumes a linear ramp from 0 V to $V_{DD(min)}$ within 200 ms. During this time $V_{IH} < V_{DD}$ and $V_{DDQ} \leq V_{DD}$.

Capacitance

Parameter ^[13]	Description	Test Conditions	100-pin TQFP Max	Unit
C_{IN}	Input capacitance	$T_A = 25^\circ\text{C}$, $f = 1\text{ MHz}$, $V_{DD} = 3.3\text{ V}$, $V_{DDQ} = 3.3\text{ V}$	5	pF
C_{CLOCK}	Clock input capacitance		5	pF
C_{IO}	I/O capacitance		5	pF

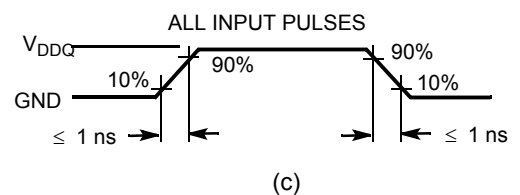
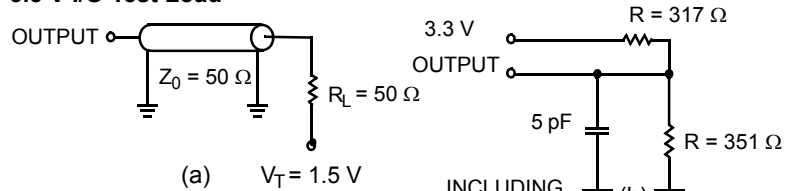
Thermal Resistance

Parameter ^[13]	Description	Test Conditions	100-pin TQFP Package	Unit
Θ_{JA}	Thermal resistance (junction to ambient)	Test conditions follow standard test methods and procedures for measuring thermal impedance, according to EIA/JESD51.	30.32	$^\circ\text{C/W}$
Θ_{JC}	Thermal resistance (junction to case)		6.85	$^\circ\text{C/W}$

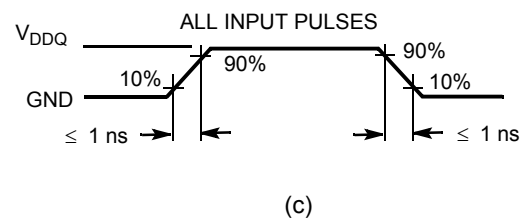
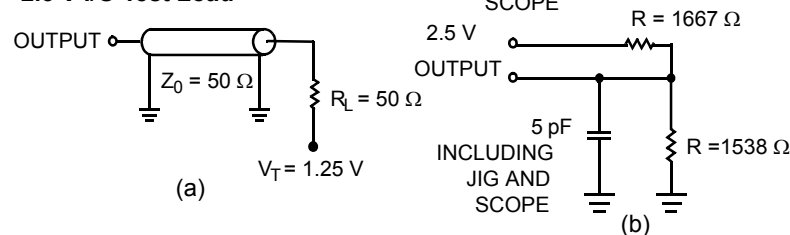
AC Test Loads and Waveforms

Figure 2. AC Test Loads and Waveforms

3.3 V I/O Test Load



2.5 V I/O Test Load



Note

13. Tested initially and after any design or process changes that may affect these parameters.

Switching Characteristics

Over the Operating Range

Parameter [14, 15]	Description	-100		Unit
		Min	Max	
t_{POWER}	$V_{DD}(\text{typical})$ to the first access [16]	1	–	ms
Clock				
t_{CYC}	Clock cycle time	10	–	ns
t_{CH}	Clock HIGH	4.0	–	ns
t_{CL}	Clock LOW	4.0	–	ns
Output Times				
t_{CDV}	Data output valid after CLK rise	–	8.0	ns
t_{DOH}	Data output hold after CLK rise	2.0	–	ns
t_{CLZ}	Clock to low Z [17, 18, 19]	0	–	ns
t_{CHZ}	Clock to high Z [17, 18, 19]	–	3.5	ns
$t_{OE\overline{V}}$	\overline{OE} LOW to output valid	–	3.5	ns
$t_{OE\overline{L}Z}$	\overline{OE} LOW to output low Z [17, 18, 19]	0	–	ns
$t_{OE\overline{H}Z}$	\overline{OE} HIGH to output high Z [17, 18, 19]	–	3.5	ns
Setup Times				
t_{AS}	Address setup before CLK rise	2.0	–	ns
t_{ALS}	ADV/LD setup before CLK rise	2.0	–	ns
t_{WES}	\overline{WE} , \overline{BW}_X setup before CLK rise	2.0	–	ns
t_{CENS}	\overline{CEN} setup before CLK rise	2.0	–	ns
t_{DS}	Data input setup before CLK rise	2.0	–	ns
t_{CES}	Chip enable setup before CLK rise	2.0	–	ns
Hold Times				
t_{AH}	Address hold after CLK rise	0.5	–	ns
t_{ALH}	ADV/LD hold after CLK rise	0.5	–	ns
t_{WEH}	\overline{WE} , \overline{BW}_X hold after CLK rise	0.5	–	ns
t_{CENH}	\overline{CEN} hold after CLK rise	0.5	–	ns
t_{DH}	Data input hold after CLK rise	0.5	–	ns
t_{CEH}	Chip enable hold after CLK rise	0.5	–	ns

Notes

14. Timing reference level is 1.5 V when $V_{DDQ} = 3.3$ V and is 1.25 V when $V_{DDQ} = 2.5$ V.

15. Test conditions shown in (a) of Figure 2 on page 9, unless otherwise noted.

16. This part has a voltage regulator internally; t_{POWER} is the time that the power needs to be supplied above $V_{DD(\text{minimum})}$ initially before a read or write operation can be initiated.

17. t_{CHZ} , t_{CLZ} , $t_{OE\overline{L}Z}$, and $t_{OE\overline{H}Z}$ are specified with AC test conditions shown in part (b) of Figure 2 on page 9. Transition is measured ± 200 mV from steady-state voltage.

18. At any voltage and temperature, $t_{OE\overline{H}Z}$ is less than $t_{OE\overline{L}Z}$ and t_{CHZ} is less than t_{CLZ} to eliminate bus contention between SRAMs when sharing the same data bus. These specifications do not imply a bus contention condition, but reflect parameters guaranteed over worst case user conditions. Device is designed to achieve tri-state prior to low Z under the same system conditions.

19. This parameter is sampled and not 100% tested.

Figure 3. Read/Write Waveforms [20, 21, 22]



22. Order of the Burst sequence is determined by the status of the MODE (0 = Linear, 1 = Interleaved). Burst operations are optional.

Switching Waveforms (continued)

Figure 4. NOP, STALL and DESELECT Cycles [23, 24, 25]

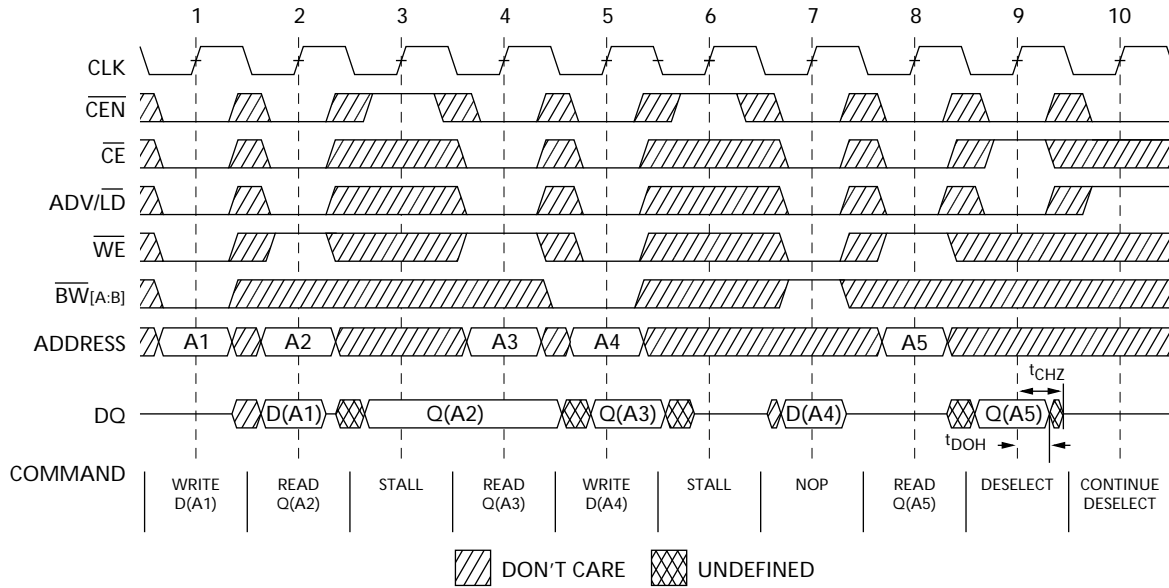
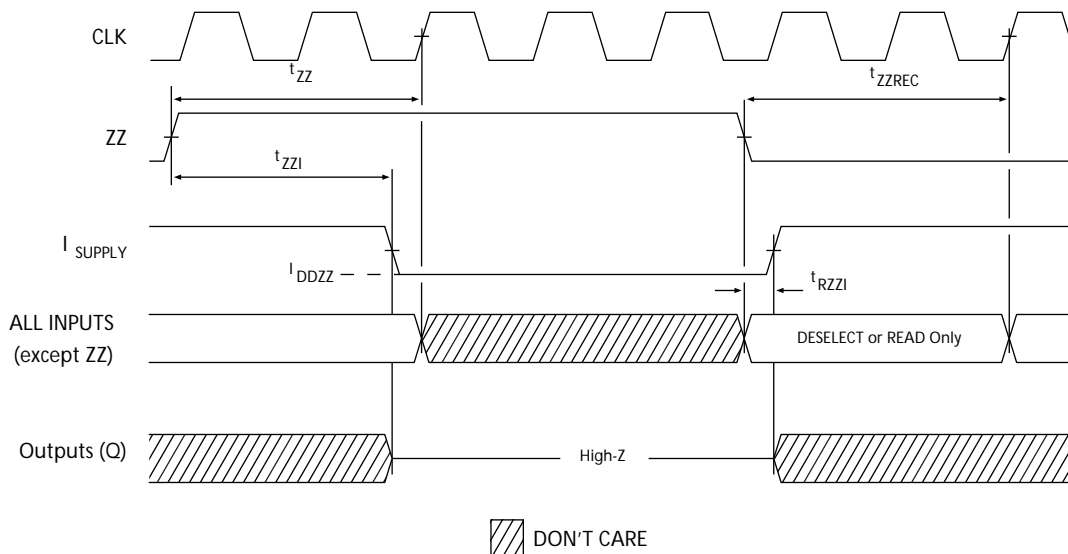


Figure 5. ZZ Mode Timing [26, 27]



Notes

23. For this waveform ZZ is tied low.

24. When \overline{CE} is LOW, \overline{CE}_1 is LOW, \overline{CE}_2 is HIGH and \overline{CE}_3 is LOW. When \overline{CE} is HIGH, \overline{CE}_1 is HIGH or \overline{CE}_2 is LOW or \overline{CE}_3 is HIGH.

25. The IGNORE CLOCK EDGE or STALL cycle (Clock 3) illustrates \overline{CEN} being used to create a pause. A write is not performed during this cycle.

26. Device must be deselected when entering ZZ mode. See truth table for all possible signal conditions to deselect the device.

27. DQs are in high Z when exiting ZZ sleep mode.



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Ordering Code Definitions

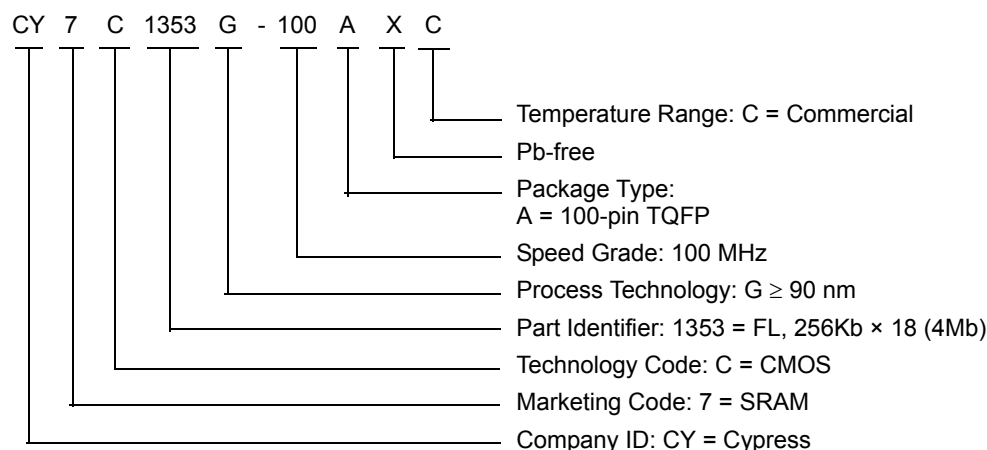
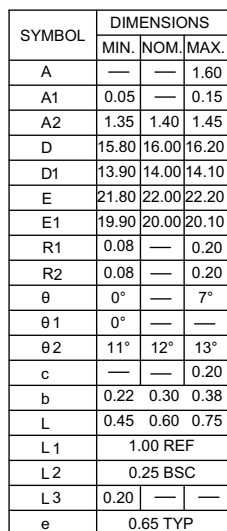


Figure 6. 100-pin TQFP (16 × 22 × 1.6 mm) A100RA Package Outline, 51-85050



1. ALL DIMENSIONS ARE IN MILLIMETERS.
2. BODY LENGTH DIMENSION DOES NOT INCLUDE MOLD PROTRUSION/END FLASH.
MOLD PROTRUSION/END FLASH SHALL NOT EXCEED 0.0098 in (0.25 mm) PER SIDE.
BODY LENGTH DIMENSIONS ARE MAX PLASTIC BODY SIZE INCLUDING MOLD MISMATCH.
3. JEDEC SPECIFICATION NO. REF: MS-026.

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Acronyms

Acronym	Description
CMOS	Complementary Metal Oxide Semiconductor
$\overline{\text{CE}}$	Chip Enable
$\overline{\text{CEN}}$	Clock Enable
EIA	Electronic Industries Alliance
I/O	Input/Output
JEDEC	Joint Electron Devices Engineering Council
NoBL	No Bus Latency
$\overline{\text{OE}}$	Output Enable
SRAM	Static Random Access Memory
TQFP	Thin Quad Flat Pack
TTL	Transistor-Transistor Logic
$\overline{\text{WE}}$	Write Enable

Document Conventions

Units of Measure

Symbol	Unit of Measure
°C	degree Celsius
MHz	megahertz
μA	microampere
mA	milliampere
ms	millisecond
mV	millivolt
ns	nanosecond
Ω	ohm
%	percent
pF	picofarad
V	volt
W	watt

Errata

This section describes the Ram9 NoBL ZZ pin issue. Details include trigger conditions, the devices affected, proposed workaround and silicon revision applicability. Please contact your local Cypress sales representative if you have further questions.

Part Numbers Affected

Density & Revision	Package Type	Operating Range
4Mb-Ram9 NoBL™ SRAMs: CY7C135*G	100-pin TQFP	Commercial

Product Status

All of the devices in the Ram9 4Mb NoBL family are qualified and available in production quantities.

Ram9 NoBL ZZ Pin Issues Errata Summary

The following table defines the errata applicable to available Ram9 4Mb NoBL family devices.

Item	Issues	Description	Device	Fix Status
1.	ZZ Pin	When asserted HIGH, the ZZ pin places device in a “sleep” condition with data integrity preserved. The ZZ pin currently does not have an internal pull-down resistor and hence cannot be left floating externally by the user during normal mode of operation.	4M-Ram9 (90nm)	For the 4M Ram9 (90 nm) devices, there is no plan to fix this issue.

1. ZZ Pin Issue

■ PROBLEM DEFINITION

The problem occurs only when the device is operated in the normal mode with ZZ pin left floating. The ZZ pin on the SRAM device does not have an internal pull-down resistor. Switching noise in the system may cause the SRAM to recognize a HIGH on the ZZ input, which may cause the SRAM to enter sleep mode. This could result in incorrect or undesirable operation of the SRAM.

■ TRIGGER CONDITIONS

Device operated with ZZ pin left floating.

■ SCOPE OF IMPACT

When the ZZ pin is left floating, the device delivers incorrect data.

■ WORKAROUND

Tie the ZZ pin externally to ground.

■ FIX STATUS

For the 4M Ram9 (90 nm) devices, there is no plan to fix this issue.

Document History Page

Document Title: CY7C1353G, 4-Mbit (256K × 18) Flow-Through SRAM with NoBL™ Architecture Document Number: 38-05515				
Rev.	ECN No.	Issue Date	Orig. of Change	Description of Change
**	224363	See ECN	RKF	New data sheet.
*A	288431	See ECN	VBL	Updated Features (Removed 66 MHz frequency related information). Updated Selection Guide (Removed 66 MHz frequency related information). Updated Electrical Characteristics (Removed 66 MHz frequency related information). Updated Switching Characteristics (Removed 66 MHz frequency related information). Updated Ordering Information (Updated part numbers (Removed 66 MHz frequency related information, changed TQFP package in Ordering Information section to Pb-free TQFP)).
*B	333626	See ECN	SYT	Updated Features (Removed 117 MHz frequency related information). Updated Selection Guide (Removed 117 MHz frequency related information). Updated Pin Configuration (Modified Address Expansion balls in the pinouts for 100-pin TQFP Packages according to JEDEC standards). Updated Pin Definitions . Updated Functional Overview (Updated ZZ Mode Electrical Characteristics (Replaced “Snooze” with “Sleep”)). Updated Truth Table (Replaced “Snooze” with “Sleep”). Updated Electrical Characteristics (Updated Test Conditions of V_{OL} , V_{OH} parameters, removed 117 MHz frequency related information). Updated Thermal Resistance (Replaced values of θ_{JA} and θ_{JC} parameters from TBD to their respective values). Updated Switching Characteristics (Removed 117 MHz frequency related information). Updated Ordering Information (By shading and unshading MPNs according to availability).
*C	418633	See ECN	R XU	Changed status from Preliminary to Final. Changed address of Cypress Semiconductor Corporation from “3901 North First Street” to “198 Champion Court”. Updated Electrical Characteristics (Updated Note 12 (Modified test condition from $V_{DDQ} < V_{DD}$ to $V_{DDQ} \leq V_{DD}$), changed “Input Load Current except ZZ and MODE” to “Input Leakage Current except ZZ and MODE”). Updated Ordering Information (Updated part numbers, replaced Package Name column with Package Diagram in the Ordering Information table). Updated Package Diagram (spec 51-85050 (changed revision from *A to *B)).
*D	480124	See ECN	VKN	Updated Maximum Ratings (Added the Maximum Rating for Supply Voltage on V_{DDQ} Relative to GND). Updated Ordering Information (Updated part numbers).
*E	1274724	See ECN	VKN / AESA	Updated Ordering Information (Corrected typo).
*F	2896584	03/20/2010	NJY	Updated Ordering Information (Removed obsolete part numbers from Ordering Information table). Updated Package Diagram .
*G	3033272	09/19/2010	NJY	Added Ordering Code Definitions Added Acronyms and Units of Measure Minor edits. Updated to new template.
*H	3357006	08/29/2011	PRIT	Updated Package Diagram . Updated to new template.

Document History Page (continued)

Document Title: CY7C1353G, 4-Mbit (256K × 18) Flow-Through SRAM with NoBL™ Architecture Document Number: 38-05515				
Rev.	ECN No.	Issue Date	Orig. of Change	Description of Change
*I	3619154	05/16/2012	PRIT	Updated Features (Removed 133 MHz frequency related information). Updated Functional Description (Removed the Note “For best-practices recommendations, please refer to the Cypress application note <i>System Design Guidelines</i> on www.cypress.com .” and its reference, removed 133 MHz frequency related information). Updated Selection Guide (Removed 133 MHz frequency related information). Updated Operating Range (Removed Industrial Temperature Range). Updated Electrical Characteristics (Removed 133 MHz frequency related information). Updated Switching Characteristics (Removed 133 MHz frequency related information). Replaced all instances of IO with I/O across the document.
*J	3754982	09/25/2012	PRIT	No technical updates. Completing Sunset Review.
*K	3980362	04/24/2013	PRIT	Added Errata .
*L	4038283	06/24/2013	PRIT	Added Errata Footnotes. Updated to new template.
*M	4149033	10/07/2013	PRIT	Updated Errata .
*N	4539104	10/15/2014	PRIT	Updated Package Diagram : spec 51-85050 – Changed revision from *D to *E. Completing Sunset Review.
*O	4572829	11/18/2014	PRIT	Updated Functional Description : Added “For a complete list of related documentation, click here .” at the end.
*P	5512557	11/07/2016	PRIT	Updated Package Diagram : spec 51-85050 – Changed revision from *E to *F. Updated to new template. Completing Sunset Review.

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